Search Notes				

Application/Control	No. Applicant(s) Reexaminat	/Patent under ion
10/069,750	YOON ET A	AL.
Examiner	Art Unit	
George R. Evanisko	3762	

SEARCHED					
Class	Subclass	Date	Examiner		
same		4/14/2006	~		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
	4/14/2006	<i></i>		
		Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
interference search attached	4/14/2006	~		